Document Number: MRF19085-2
Rev. 10, 10/2008

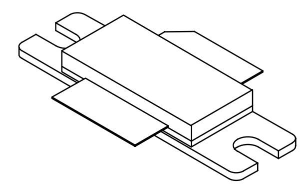
RoHS

RF Power Field Effect Transistor

N-Channel Enhancement-Mode Lateral MOSFET

MRF19085LR3

**1930-1990 MHz, 90 W, 26 V
LATERAL N-CHANNEL
RF POWER MOSFET**



**CASE 465-06, STYLE 1
NI-780**

Designed for PCN and PCS base station applications with frequencies from 1900 to 2000 MHz. Suitable for TDMA, CDMA and multicarrier amplifier applications.

- Typical 2-Carrier N-CDMA Performance for V_{DD} = 26 Volts, I_{DQ} = 850 mA, P_{out} = 18 Watts Avg., f1 = 1930 MHz, f2 = 1932.5 MHz IS-95 CDMA (Pilot, Sync, Paging, Traffic Codes 8 Through 13) 1.2288 MHz Channel Bandwidth Carrier. Adjacent Channels Measured over a 30 kHz Bandwidth at f1 -885 Khz and f2 +885 kHz. Distortion Products Measured over 1.2288 MHz Bandwidth at f1 -2.5 MHz and f2 +2.5 MHz. Peak/Avg. = 9.8 dB @ 0.01% Probability on CCDF.
  Output Power — 18 Watts Avg.
  Power Gain — 13.0 dB
  Efficiency — 23%
  ACPR — -51 dB
  IM3 — -36.5 dBc
- Capable of Handling 5:1 VSWR, @ 26 Vdc, 1960 MHz, 90 Watts CW Output Power

Features

- Internally Matched for Ease of Use
- High Gain, High Efficiency and High Linearity
- Integrated ESD Protection
- Designed for Maximum Gain and Insertion Phase Flatness
- Excellent Thermal Stability
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Available with Low Gold Plating Thickness on Leads. L Suffix Indicates 40μ″ Nominal.
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 Inch Reel.

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V_{GS}	-0.5, +15	Vdc
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	273 1.56	W W/°C
Storage Temperature Range	T_{stg}	- 65 to +150	°C
Case Operating Temperature	T_C	150	°C
Operating Junction Temperature	T_J	200	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value (1)	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	0.79	°C/W

Table 3. ESD Protection Characteristics

Test Conditions	Class
Human Body Model	1 (Minimum)
Machine Model	M3 (Minimum)

1. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers.* Go to http://www.freescale.com/rf. Select Documentation/Application Notes - AN1955.

Table 4. Electrical Characteristics (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Off Characteristics					
Drain-Source Breakdown Voltage (V_{GS} = 0 Vdc, I_D = 100 μAdc)	$V_{(BR)DSS}$	65	—	—	Vdc
Zero Gate Voltage Drain Current (V_{DS} = 26 Vdc, V_{GS} = 0 Vdc)	I_{DSS}	—	—	10	μAdc
Gate-Source Leakage Current (V_{GS} = 5 Vdc, V_{DS} = 0 Vdc)	I_{GSS}	—	—	1	μAdc
On Characteristics (DC)					
Gate Threshold Voltage (V_{DS} = 10 Vdc, I_D = 200 μAdc)	$V_{GS(th)}$	2	—	4	Vdc
Gate Quiescent Voltage (V_{DS} = 26 Vdc, I_D = 850 mAdc)	$V_{GS(Q)}$	2.5	3.5	4.5	Vdc
Drain-Source On-Voltage (V_{GS} = 10 Vdc, I_D = 2 Adc)	$V_{DS(on)}$	—	0.18	0.210	Vdc
Forward Transconductance (V_{DS} = 10 Vdc, I_D = 2 Adc)	g_{fs}	—	6	—	S
Dynamic Characteristics					
Reverse Transfer Capacitance (1) (V_{DS} = 26 Vdc, V_{GS} = 0, f = 1.0 MHz)	C_{rss}	—	3.6	—	pF
Functional Tests (In Freescale Test Fixture, 50 ohm system) 2-Carrier N-CDMA, 1.2288 MHz Channel Bandwidth Carriers. Peak/Avg. = 9.8 dB @ 0.01% Probability on CCDF.					
Common-Source Amplifier Power Gain (V_{DD} = 26 Vdc, P_{out} = 18 W Avg., I_{DQ} = 850 mA, f1 = 1930 MHz, f2 = 1932.5 MHz)	G_{ps}	12	13	—	dB
Drain Efficiency (V_{DD} = 26 Vdc, P_{out} = 18 W Avg., I_{DQ} = 850 mA, f1 = 1930 MHz, f2 = 1932.5 MHz)	η	21	23	—	%
3rd Order Intermodulation Distortion (V_{DD} = 26 Vdc, P_{out} = 18 W Avg., I_{DQ} = 850 mA, f1 = 1930 MHz, f2 = 1932.5 MHz; IM3 measured over 1.2288 MHz bandwidth @ f1 = -2.5 MHz and f2 = +2.5 MHz)	IMD	—	-36.5	-35	dBc
Adjacent Channel Power Ratio (V_{DD} = 26 Vdc, P_{out} = 18 W Avg., I_{DQ} = 850 mA, f1 = 1930 MHz, f2 = 1932.5 MHz; ACPR measured over 30 kHz bandwidth @ f1 = -885 MHz and f2 = +885 MHz)	ACPR	—	-51	-48	dBc
Input Return Loss (V_{DD} = 26 Vdc, P_{out} = 18 W Avg., I_{DQ} = 850 mA, f1 = 1930 MHz, f2 = 1932.5 MHz)	IRL	—	-12	-9	dB

1. Part is internally matched both on input and output.

(continued)

Table 4. Electrical Characteristics (T_C = 25°C unless otherwise noted) **(continued)**

Characteristic	Symbol	Min	Typ	Max	Unit
Functional Tests (In Freescale Test Fixture)					
Two-Tone Common-Source Amplifier Power Gain (V_{DD} = 26 Vdc, P_{out} = 90 W PEP, I_{DQ} = 850 mA, f = 1930 MHz and 1990 MHz, Tone Spacing = 100 kHz)	G_{ps}	—	13	—	dB
Two-Tone Drain Efficiency (V_{DD} = 26 Vdc, P_{out} = 90 W PEP, I_{DQ} = 850 mA, f = 1930 MHz and 1990 MHz, Tone Spacing = 100 kHz)	η	—	36	—	%
3rd Order Intermodulation Distortion (V_{DD} = 26 Vdc, P_{out} = 90 W PEP, I_{DQ} = 850 mA, f = 1930 MHz and 1990 MHz, Tone Spacing = 100 kHz)	IMD	—	-31	—	dBc
Input Return Loss (V_{DD} = 26 Vdc, P_{out} = 90 W PEP, I_{DQ} = 850 mA, f = 1930 MHz and 1990 MHz, Tone Spacing = 100 kHz)	IRL	—	-12	—	dB
P_{out}, 1 dB Compression Point (V_{DD} = 26 Vdc, I_{DQ} = 850 mA, f = 1990 MHz)	P1dB	—	90	—	W

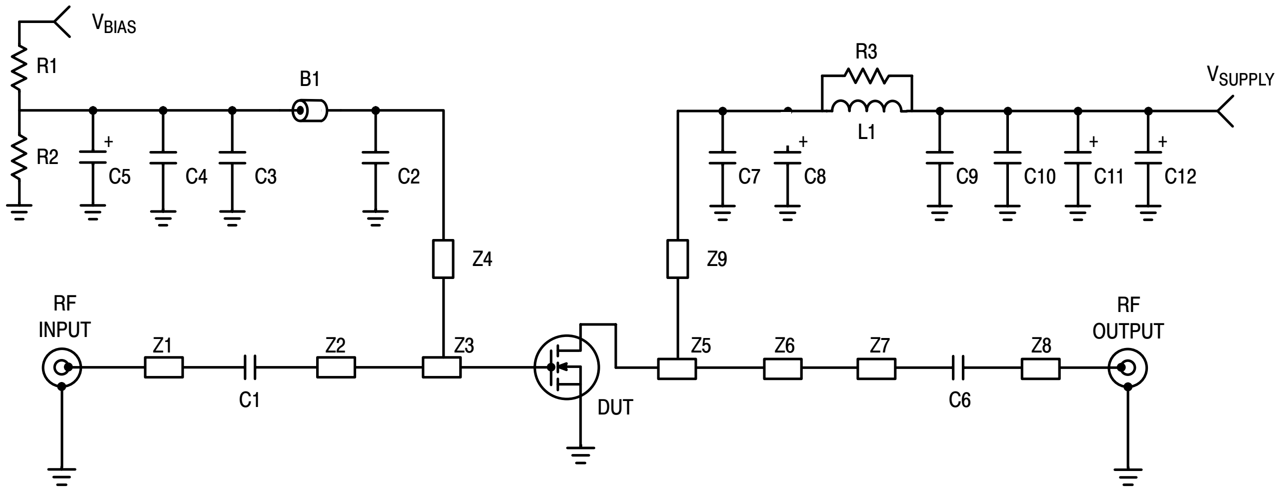
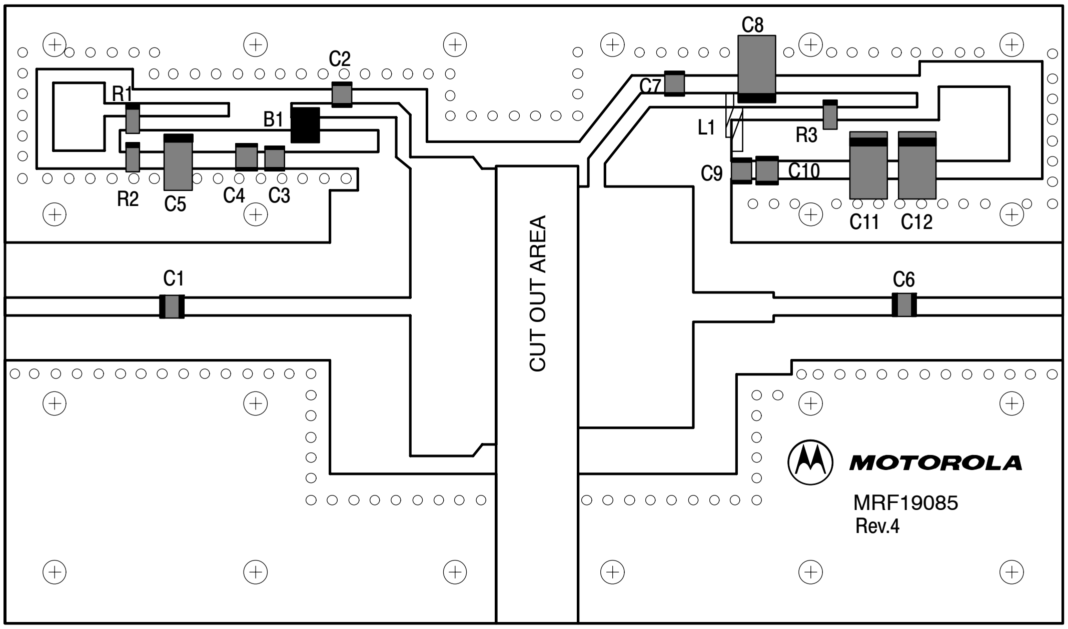


Figure 1. 1930 - 1990 MHz 2-Carrier N-CDMA Test Circuit Schematic

Table 5. 1930 - 1990 MHz 2-Carrier N-CDMA Test Circuit Component Designations and Values

Part	Description	Part Number	Manufacturer
B1	Short Ferrite Bead	2743019447	Fair Rite
C1	51 pF Chip Capacitor	ATC100B510JT500XT	ATC
C2, C7	5.1 pF Chip Capacitors	ATC100B5R1JT500XT	ATC
C3, C9	1000 pF Chip Capacitors	ATC100B102JT500XT	ATC
C4, C10	0.1 μF Chip Capacitors	CDR33BX104AKYS	Kemet
C5	0.1 μF Tantalum Surface Mount Capacitor	T491C105M050AT	Kemet
C6	10 pF Chip Capacitor	ATC100B100JT500XT	ATC
C8	10 μF Tantalum Surface Mount Capacitor	T495D106K035AT	Kemet
C11, C12	22 μF Tantalum Surface Mount Capacitors	T491D226K035AT	Kemet
L1	1 Turn, 20 AWG, 0.100″ ID		
R1	1.0 kΩ, 1/4 W Chip Resistor	CRCW12061001FKEA	Vishay
R2	220 kΩ, 1/4 W Chip Resistor	CRCW12062200FKEA	Vishay
R3	10 Ω, 1/4 W Chip Resistor	CRCW120610R0FKEA	Vishay
Z1	Microstrip	0.750″ x 0.0840″	
Z2	Microstrip	1.090″ x 0.0840″	
Z3	Microstrip	0.400″ x 1.400″	
Z4	Microstrip	0.520″ x 0.050″	
Z5	Microstrip	0.540″ x 1.133″	
Z6	Microstrip	0.400″ x 0.140″	
Z7	Microstrip	0.555″ x 0.0840″	
Z8	Microstrip	0.720″ x 0.0840″	
Z9	Microstrip	0.560″ x 0.070″	
Board	0.030″ Glass Teflon®	GX-0300-55-22, ε_r = 2.55	Arlon
PCB	Etched Circuit Boards	MRF19085 Rev. 4	CMR



Freescale has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescale Semiconductor signature/logo. PCBs may have either Motorola or Freescale markings during the transition period. These changes will have no impact on form, fit or function of the current product.

Figure 2. 1930 - 1990 MHz 2-Carrier N-CDMA Test Circuit Component Layout

TYPICAL CHARACTERISTICS

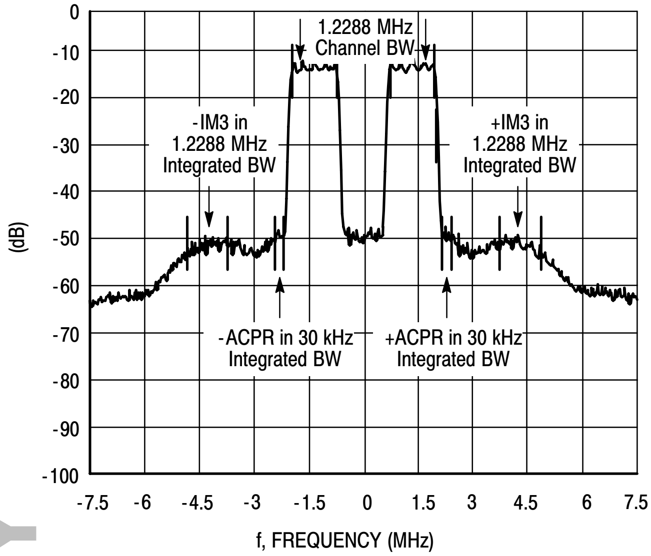


Figure 3. 2-Carrier N-CDMA Spectrum

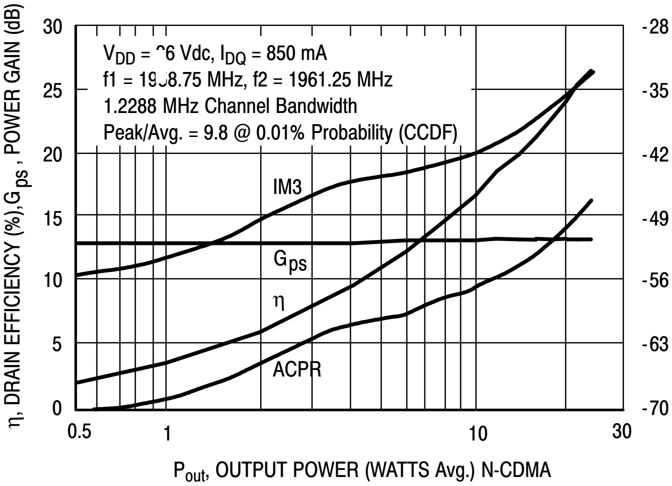


Figure 4. 2-Carrier N-CDMA ACPR, IM3, Power Gain and Drain Efficiency versus Output Power

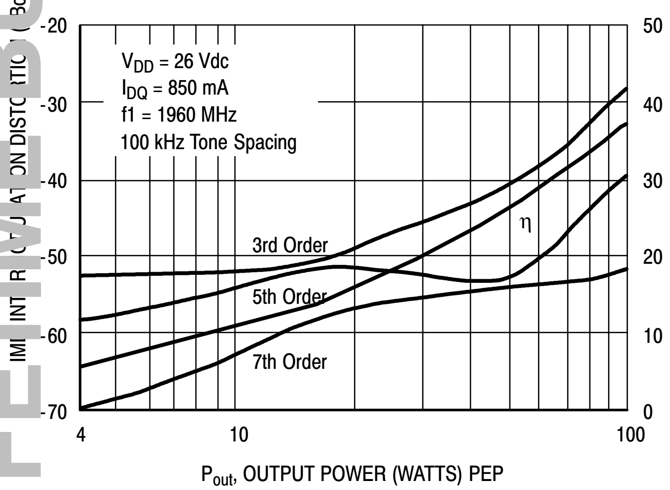


Figure 5. Intermodulation Distortion Products versus Output Power

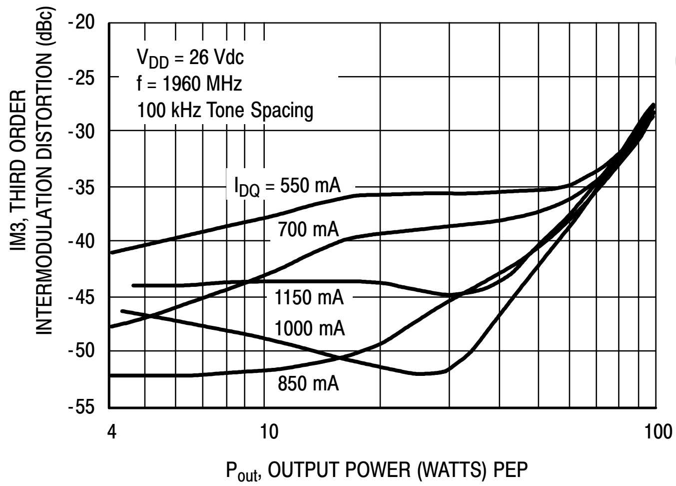


Figure 6. Third Order Intermodulation Distortion versus Output Power and I_{DQ}

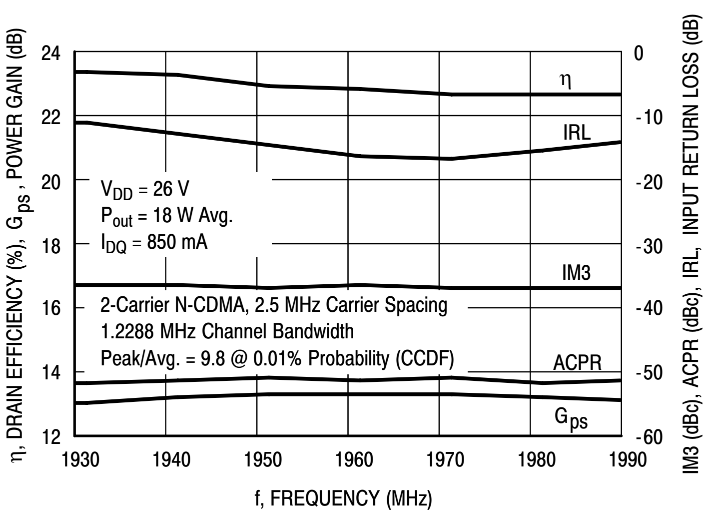


Figure 7. 2-Carrier N-CDMA Broadband Performance

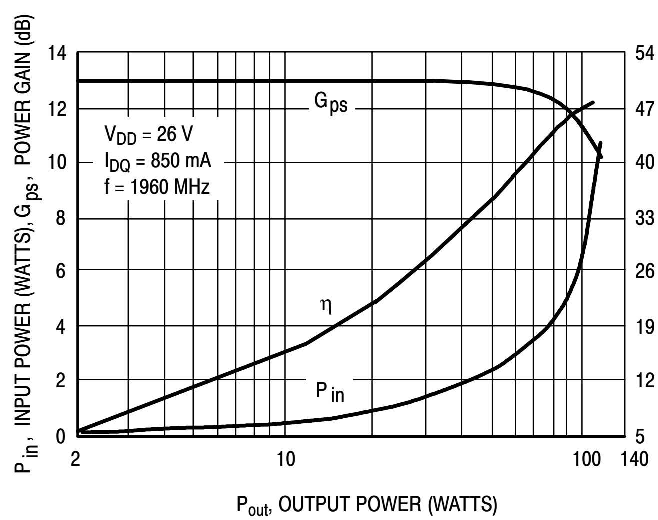


Figure 8. CW Performance

TYPICAL CHARACTERISTICS

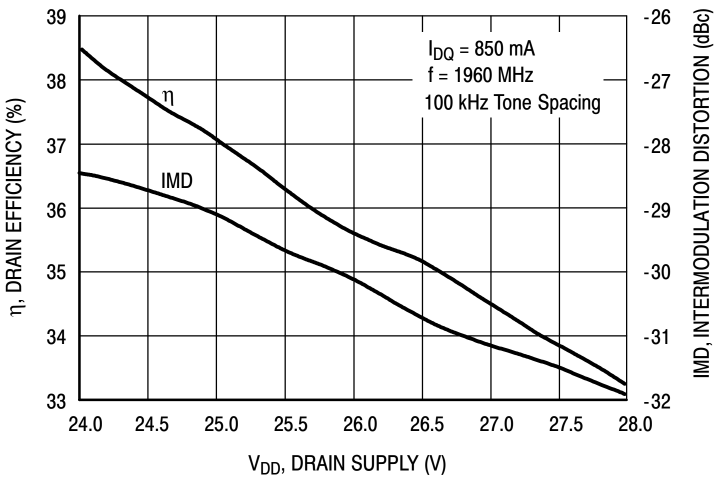


Figure 9. Two-Tone Intermodulation Distortion and Drain Efficiency versus Drain Supply

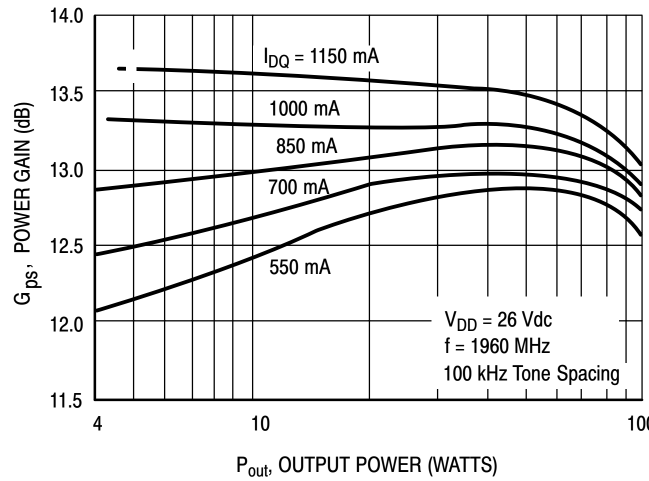


Figure 10. Two-Tone Power Gain versus Output Power

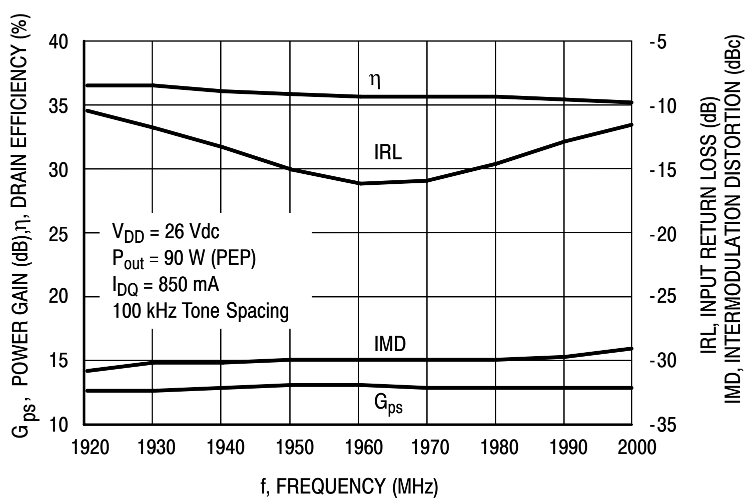
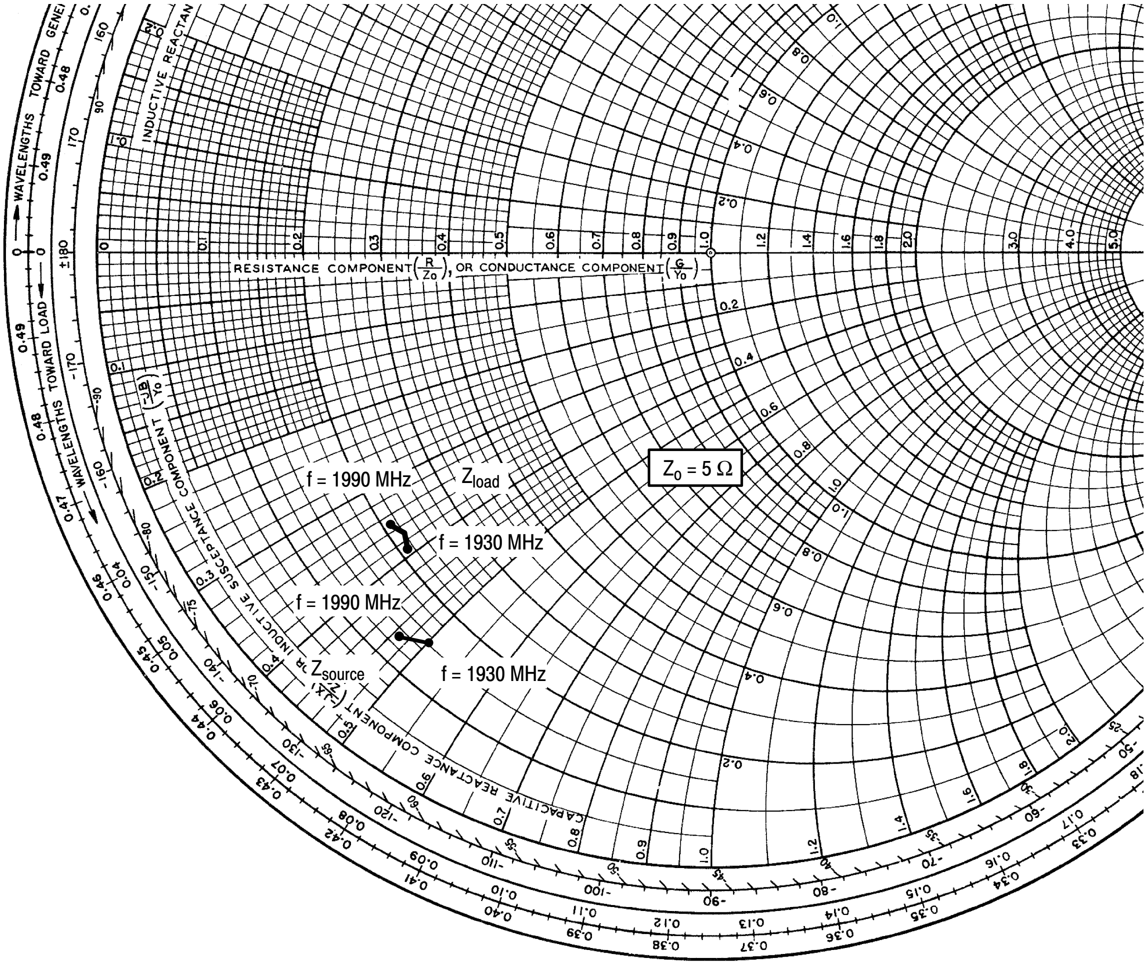


Figure 11. Two-Tone Broadband Performance



V_{DD} = 26 V, I_{DQ} = 850 mA, P_{out} = 18 W Avg.

f MHz	Z_{source} Ω	Z_{load} Ω
1930	0.75 - j2.50	1.05 - j1.95
1960	0.70 - j2.40	1.10 - j1.85
1990	0.65 - j2.35	1.05 - j1.75

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

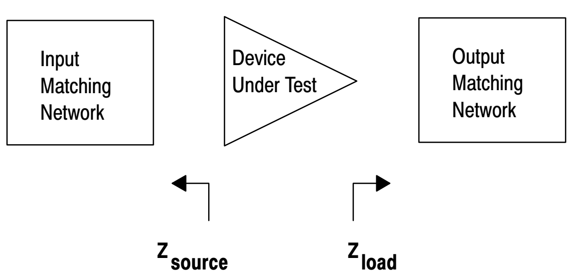
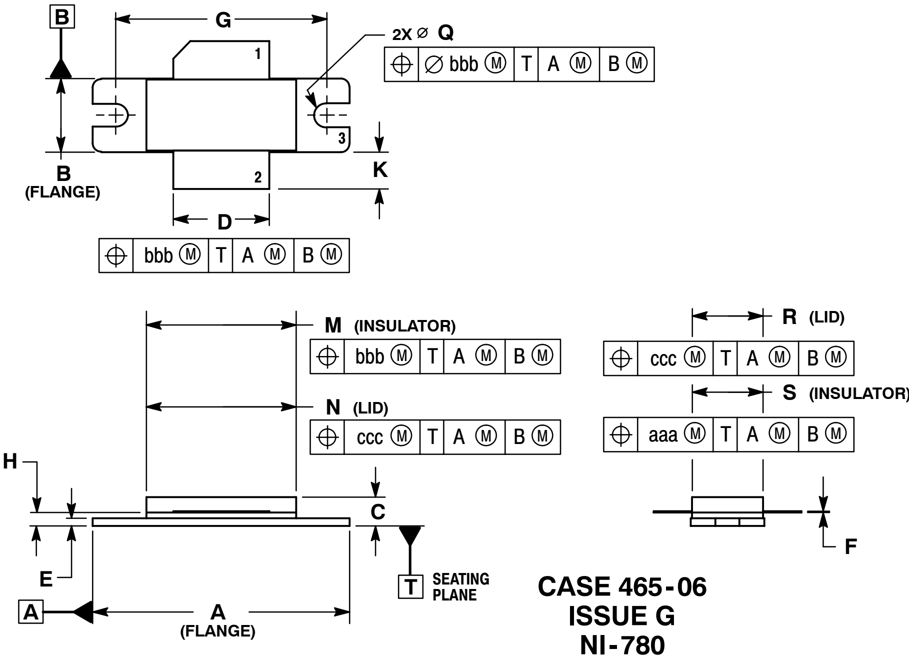


Figure 12. Series Equivalent Source and Load Impedance

PACKAGE DIMENSIONS



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DELETED
4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

DIM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	1.335	1.345	33.91	34.16
B	0.380	0.390	9.65	9.91
C	0.125	0.170	3.18	4.32
D	0.495	0.505	12.57	12.83
E	0.035	0.045	0.89	1.14
F	0.003	0.006	0.08	0.15
G	1.100 BSC		27.94 BSC	
H	0.057	0.067	1.45	1.70
K	0.170	0.210	4.32	5.33
M	0.774	0.786	19.66	19.96
N	0.772	0.788	19.60	20.00
Q	⌀.118	⌀.138	⌀3.00	⌀3.51
R	0.365	0.375	9.27	9.53
S	0.365	0.375	9.27	9.52
aaa	0.005 REF		0.127 REF	
bbb	0.010 REF		0.254 REF	
ccc	0.015 REF		0.381 REF	

STYLE 1:
PIN 1. DRAIN
2. GATE
3. SOURCE

CASE 465-06
ISSUE G
NI-780
MRF19085LR3

PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

Application Notes

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
10	Oct. 2008	• Data sheet revised to reflect part status change, p. 1, including use of applicable overlay. • Modified data sheet to reflect RF Test Reduction described in Product and Process Change Notification number, PCN12779, p. 1, 2 • Updated Part Numbers in Table 5, Component Designations and Values, to RoHS compliant part numbers, p. 4 • Added Product Documentation and Revision History, p. 10

How to Reach Us:

Home Page:
www.freescale.com

Web Support:
http://www.freescale.com/support

USA/Europe or Locations Not Listed:
Freescale Semiconductor, Inc.
Technical Information Center, EL516
2100 East Elliot Road
Tempe, Arizona 85284
1-800-521-6274 or +1-480-768-2130
www.freescale.com/support

Europe, Middle East, and Africa:
Freescale Halbleiter Deutschland GmbH
Technical Information Center
Schatzbogen 7
81829 Muenchen, Germany
+44 1296 380 456 (English)
+46 8 52200080 (English)
+49 89 92103 559 (German)
+33 1 69 35 48 48 (French)
www.freescale.com/support

Japan:
Freescale Semiconductor Japan Ltd.
Headquarters
ARCO Tower 15F
1-8-1, Shimo-Meguro, Meguro-ku,
Tokyo 153-0064
Japan
0120 191014 or +81 3 5437 9125
support.japan@freescale.com

Asia/Pacific:
Freescale Semiconductor China Ltd.
Exchange Building 23F
No. 118 Jianguo Road
Chaoyang District
Beijing 100022
China
+86 10 5879 8000
support.asia@freescale.com

For Literature Requests Only:
Freescale Semiconductor Literature Distribution Center
P.O. Box 5405
Denver, Colorado 80217
1-800-441-2447 or +1-303-675-2140
Fax: +1-303-675-2150
LDCForFreescaleSemiconductor@hibbertgroup.com

Document Number: MRF19085-2
Rev. 10, 10/2008